





EC26 25 ET

Frequency Tolerance/Stability — ±25ppm Maximum

Operating Temperature Range --40°C to +85°C

TS -25.920M

Nominal Frequency 25.920MHz

Pin 1 Connection
Tri-State (High Impedance)

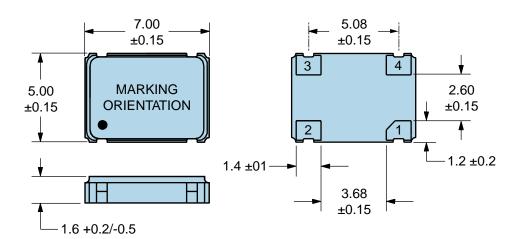
- Duty Cycle 50 ±10(%)

| ELECTRICAL SPECIFICATIONS             |   |  |  |
|---------------------------------------|---|--|--|
| Nominal Frequency                     | 25.920MHz   |  |  |
| Frequency Tolerance/Stability         | ±25ppm Maximum (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over the Operating Temperature Range, Supply Voltage Change, Ouput Load Change, First Year Aging at 25°C, Shock, and Vibration) |  |  |
| Operating Temperature Range           | -40°C to +85°C  |  |  |
| Supply Voltage                        | 3.3Vdc ±10%   |  |  |
| Input Current                         | 10mA Maximum  |  |  |
| Output Voltage Logic High (Voh)       | 90% of Vdd Minimum (IOH=-8mA)   |  |  |
| Output Voltage Logic Low (Vol)        | 10% of Vdd Maximum (IOL=+8mA)   |  |  |
| Rise/Fall Time                        | 5nSec Maximum (w/15pF Load), 7nSec Maximum (w/30pF Load) (Measured at 20% to 80% of waveform)   |  |  |
| Duty Cycle                            | 50 ±10(%) (Measured at 50% of waveform)   |  |  |
| Load Drive Capability                 | 30pF Maximum  |  |  |
| Output Logic Type                     | CMOS  |  |  |
| Pin 1 Connection                      | Tri-State (High Impedance)  |  |  |
| Tri-State Input Voltage (Vih and Vil) | +0.7Vdd Minimum or No Connect to Enable Output, +0.3Vdd Maximum to Disable Output (High Impedance)  |  |  |
| Standby Current                       | 10µA Maximum (Disabled Output: High Impedance)  |  |  |
| RMS Phase Jitter                      | 1pSec Maximum (12kHz to 20MHz offset frequency)   |  |  |
| Start Up Time                         | 10mSec Maximum  |  |  |
| Storage Temperature Range             | -55°C to +125°C   |  |  |

| ENVIRONMENTAL & MECHANICAL SPECIFICATIONS |   |  |
|---|---|--|
| ESD Susceptibility                        | MIL-STD-883, Method 3015, Class 1, HBM: 1500V |  |
| Fine Leak Test                            | MIL-STD-883, Method 1014, Condition A         |  |
| Flammability                              | UL94-V0                                       |  |
| Gross Leak Test                           | MIL-STD-883, Method 1014, Condition C         |  |
| Mechanical Shock                          | MIL-STD-883, Method 2002, Condition B         |  |
| Moisture Resistance                       | MIL-STD-883, Method 1004                      |  |
| Moisture Sensitivity                      | J-STD-020, MSL 1                              |  |
| Resistance to Soldering Heat              | MIL-STD-202, Method 210, Condition K          |  |
| Resistance to Solvents                    | MIL-STD-202, Method 215                       |  |
| Solderability                             | MIL-STD-883, Method 2003                      |  |
| Temperature Cycling                       | MIL-STD-883, Method 1010, Condition B         |  |
| Vibration                                 | MIL-STD-883, Method 2007, Condition A         |  |



### **MECHANICAL DIMENSIONS (all dimensions in millimeters)**



| PIN | CONNECTION         |
|-----|--------------------|
| 1   | Tri-State          |
| 2   | Ground/Case Ground |
| 3   | Output             |
| 4   | Supply Voltage     |

| LINE | MARKING   |
|------|---|
| 1    | ECLIPTEK  |
| 2    | 25.920M   |
| 3    | XXYZZ XX=Ecliptek Manufacturing Code Y=Last Digit of the Year ZZ=Week of the Year |

#### **Suggested Solder Pad Layout**

All Dimensions in Millimeters



All Tolerances are ±0.1



#### **OUTPUT WAVEFORM & TIMING DIAGRAM**



#### **Test Circuit for CMOS Output**



Note 1: An external 0.1µF low frequency tantalum bypass capacitor in parallel with a 0.01µF high frequency ceramic bypass capacitor close to the package ground and V<sub>DD</sub> pin is required.

Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value  $\dot{C}_L$  includes sum of all probe and fixture capacitance.



# **Recommended Solder Reflow Methods**



### **High Temperature Infrared/Convection**

| <u> </u>  |   |
|---|---|
| T <sub>s</sub> MAX to T <sub>∟</sub> (Ramp-up Rate) | 3°C/second Maximum                                |
| Preheat   |   |
| - Temperature Minimum (T <sub>S</sub> MIN)          | 150°C   |
| - Temperature Typical (T <sub>s</sub> TYP)          | 175°C   |
| - Temperature Maximum (T <sub>s</sub> MAX)          | 200°C   |
| - Time (t <sub>s</sub> MIN)                         | 60 - 180 Seconds                                  |
| Ramp-up Rate (T <sub>L</sub> to T <sub>P</sub> )    | 3°C/second Maximum                                |
| Time Maintained Above:                              |   |
| - Temperature (T∟)                                  | 217°C   |
| - Time (t∟)   | 60 - 150 Seconds                                  |
| Peak Temperature (T <sub>P</sub> )                  | 260°C Maximum for 10 Seconds Maximum              |
| Target Peak Temperature (T <sub>P</sub> Target)     | 250°C +0/-5°C                                     |
| Time within 5°C of actual peak (tp)                 | 20 - 40 seconds                                   |
| Ramp-down Rate                                      | 6°C/second Maximum                                |
| Time 25°C to Peak Temperature (t)                   | 8 minutes Maximum                                 |
| Moisture Sensitivity Level                          | Level 1   |
| Additional Notes                                    | Temperatures shown are applied to body of device. |
|   |   |



### **Recommended Solder Reflow Methods**



#### Low Temperature Infrared/Convection 240°C

| T <sub>S</sub> MAX to T <sub>L</sub> (Ramp-up Rate) | 5°C/second Maximum                                     |
|---|--|
| Preheat   |  |
| - Temperature Minimum (T <sub>s</sub> MIN)          | N/A  |
| - Temperature Typical (T <sub>S</sub> TYP)          | 150°C  |
| - Temperature Maximum (T <sub>s</sub> MAX)          | N/A  |
| - Time (t <sub>s</sub> MIN)                         | 60 - 120 Seconds                                       |
| Ramp-up Rate (T <sub>L</sub> to T <sub>P</sub> )    | 5°C/second Maximum                                     |
| Time Maintained Above:                              |  |
| - Temperature (T∟)                                  | 150°C  |
| - Time (t∟)   | 200 Seconds Maximum                                    |
| Peak Temperature (T <sub>P</sub> )                  | 240°C Maximum  |
| Target Peak Temperature (T <sub>P</sub> Target)     | 240°C Maximum 1 Time / 230°C Maximum 2 Times           |
| Time within 5°C of actual peak (tp)                 | 10 seconds Maximum 2 Times / 80 seconds Maximum 1 Time |
| Ramp-down Rate                                      | 5°C/second Maximum                                     |
| Time 25°C to Peak Temperature (t)                   | N/A  |
| Moisture Sensitivity Level                          | Level 1  |
| Additional Notes                                    | Temperatures shown are applied to body of device.      |

#### **Low Temperature Manual Soldering**

185°C Maximum for 10 seconds Maximum, 2 times Maximum. (Temperatures shown are applied to body of device.)

### **High Temperature Manual Soldering**

260°C Maximum for 5 seconds Maximum, 2 times Maximum. (Temperatures shown are applied to body of device.)